

<b>Notice of References Cited</b>	Application/Control No. 10/036,171		Applicant(s)/Patent Under Reexamination SONNENSCHNEID ET AL.	
	Examiner John P. Leubecker		Art Unit 3739	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,395,030 A	03-1995	Kuramoto et al.	227/179.1
*	B	US-6,159,146 A	12-2000	El Gazayerli, Mohamed Mounir	600/106
*	C	US-6,312,437 B1	11-2001	Kortenbach, Juergen Andrew	606/139
*	D	US-6,663,639 B1	12-2003	Laufer et al.	606/139
*	E	US-6,716,233 B1	04-2004	Whitman, Michael P.	606/219
*	F	US-6,872,214 B2	03-2005	Sonnenschein et al.	606/153
*	G	US-7,156,863 B2	01-2007	Sonnenschein et al.	606/219
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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